kroner, the US dollar equivalents are subject to exchange-rate fluctuations.

Price of back numbers

The prices of back numbers have been increased so that they are the same as the subscription rates for the volumes to be published in 1982. The prices of Volumes 1–23 of *Acta Crystallographica*, which were published before the journal was divided into two sections have been increased to the same price as the A volumes. The prices are fixed in Danish kroner and the US dollar equivalents given below are subject to exchange-rate fluctuations.

Acta Crystallographica

Complete volumes, regular price per volume

Vols. 1–23	Dkr 110	($169)
Combined Vols. 24–37	Dkr 4100	($631)
Vols. A24–A37	Dkr 1100	($169)
Vols. B24–B37	Dkr 3200	($492)

Complete volumes, reduced price for individuals

Vols. 1–23	Dkr 300	($46)
Combined Vols. 24–37	Dkr 1200	($185)
Vols. A24–A37	Dkr 300	($46)
Vols. B24–B37	Dkr 1000	($154)

Single parts

The prices of single parts are follows:

Vols. A24–A37	Dkr 275	($42)
Vols. B24–B37	Dkr 400	($62)

Single parts of Volumes 1–23 are not available.

Cumulative indexes, regular price

Vols. 11–23 (1958–1967)	Dkr 120	($18)
Vols. 24–28 (1968–1972)	Dkr 120	($18)

Cumulative indexes, reduced price for individuals

Vols. 11–23 (1958–1967)	Dkr 60	($9)
Vols. 24–28 (1968–1972)	Dkr 60	($9)

A few copies of the cumulative index for Volumes 1–10 (1948–1957) are also available, free of charge.

Journal of Applied Crystallography

Complete volumes, regular price per volume

Vols. 1–14	Dkr 1030	($158)

Complete volumes, reduced price for individuals

Vols. 1–14	Dkr 400	($62)

Single parts

The price of single parts is as follows

Vols. 1–14	Dkr 260	($40)

Orders

Orders for *Acta Crystallographica* and *Journal of Applied Crystallography* may be addressed to Munksgaard International Publishers Ltd, 35 Nørre Søgade, DK-1370 Copenhagen K, Denmark. Orders from subscribers in North America may alternatively be placed through Polycrystal Book Service, PO Box 11567, Pittsburgh, Pa. 15238, USA.

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Report of the Executive Committee for 1980

The Report of the Executive Committee for 1980 has been published in *Acta Crystallographica*, Section A [*Acta Cryst.* (1981). A**37**, 922–941]. It reports on the meetings and publications of the Union, the work of its Commissions, and the work of bodies not belonging to the Union on which the Union is represented.

Notes and News

Announcements and other items of crystallographic interest will be published under this heading at the discretion of the Editorial Board. The notes (in duplicate) should be sent to the Executive Secretary of the International Union of Crystallography (J. N. King, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England).

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The B. E. Warren Diffraction Physics Award

The fifth Bertram Eugene Warren Diffraction Physics Award will be presented at the meeting of the American Crystallographic Association in Gaithersburg, Maryland in March 1982.

This award was established by students and friends of Professor Warren on the occasion of his retirement from the Massachusetts Institute of Technology. It is to be given for an important recent contribution to the physics of solids or liquids using X-ray, neutron, or electron diffraction techniques. This includes work such as elastic or inelastic scattering studies of imperfections in crystals, or studies of liquids or amorphous materials, or developments in the diffraction theory or techniques appropriate to such problems, to give a few examples; it does not include crystal structure determinations. Previous recipients of the award have been U. Bonse and M. Hart (1970), J. D. Axe and G. Shirane (1973), J. M. Cowley and S. Iijima (1976) and F. W. Lytle, D. E. Sayres and E. A. Stern (1979).

Work that is to be eligible for this award must have been published between 1 July 1975 and 30 June 1981. There are no restrictions as to age, experience, or nationality of recipients. The award consists of a certificate and $ 1000 and is to be given every three years.

The following committee has been appointed to select the 1982 award recipient: D. L. Evans, W. B. Yelon, and B. J. Wuensch, Chairman.

The selection committee will welcome suggestions for possible recipients by January 1, 1982 from any interested persons. Suggestions should be addressed to Professor B. J. Wuensch, Room 13-4037, Department of Materials Science and Engineering, Massachusetts Institute of Technology, Cambridge, Massachusetts 02139, USA.

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ICSD – Inorganic Crystal Structure Data Base

Complementary to the well known Cambridge Crystallographic Data File, a similar file for inorganic substances has been established at the University of Bonn (G. Bergerhoff and I. D. Brown). The current file contains information on 9000 structures: chemical name, chemical formula, mineral name, unit cell, space group, coordinates, temperature factors, references, remarks. More detailed information will be given in a paper to be published in *Acta Crystallographica*. The data base will be made available by Fachinformationszentrum Energie Physik Mathematik GmbH (Dr H. Behrens), D-7514 Eggenstein-Leopoldshafen, Federal Republic of Germany, from 1982 on, in three versions:

On-line access *via* telecommunications systems (Euronet, Datex-P, *etc.*).
Leasing the up-to-date data base and retrieval programs (IBM-Fortran) at an annual rate.
Leasing only the up-to-date data base at an annual rate.

Detailed conditions are available on request from Dr Behrens at the address given above.

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New Philips powder diffractometers

At a Press Conference near Almelo, The Netherlands, on 18 September 1981 Philips demonstrated their new series of X-ray powder diffractometers. These range from a model with stand-alone microprocessor control, PW1710, to a system using a DEC PDP11 minicomputer and hard disc, PW1700. The smaller system was demonstrated with a programmed scan of a line profile, with automatic print-out on the chart of the *d* spacings; interfacing facilities are standard and background correction and area integration programs are provided. The system is also user-programmable.

The larger system was shown performing an analysis of the ash from the Mount St. Helens eruption. This was demonstrated on a graphics terminal. The complete JCPDS file is stored on disc and a second-differential peak-matching procedure is used. While the main emphasis of the software is at present on phase analysis, crystallographic analysis and profile analysis packages are under development.